

**Notice of References Cited**

Application/Control No.

10/544,210

Applicant(s)/Patent Under  
Reexamination  
TAKAHASHI ET AL.

Examiner

ADAM A. ARCIERO

Art Unit

1795

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,071,645	06-2000	Biensan et al.	429/223
*	B	US-5,487,960	01-1996	Tanaka, Mitsutoshi	429/332
*	C	US-2001/0031391 A1	10-2001	Hironaka et al.	429/94
*	D	US-5,478,674	12-1995	Miyasaka, Tsutomu	429/231.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09-293536	11-1997	Japan	Iwasaki et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IPDL PAJ JPO Machine Translation for Iwasaki et al., JP 09-293536 A (11-1997).
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.